

# Update of CGEM Digitization

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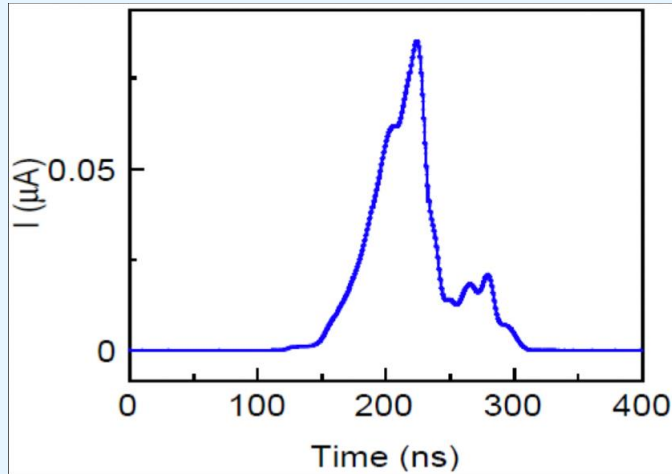
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# Introduction

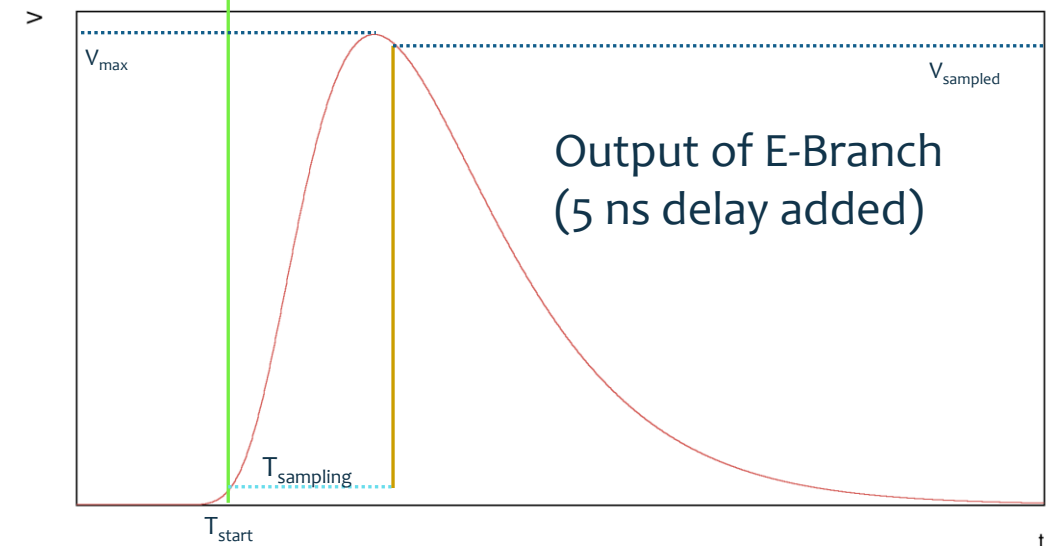
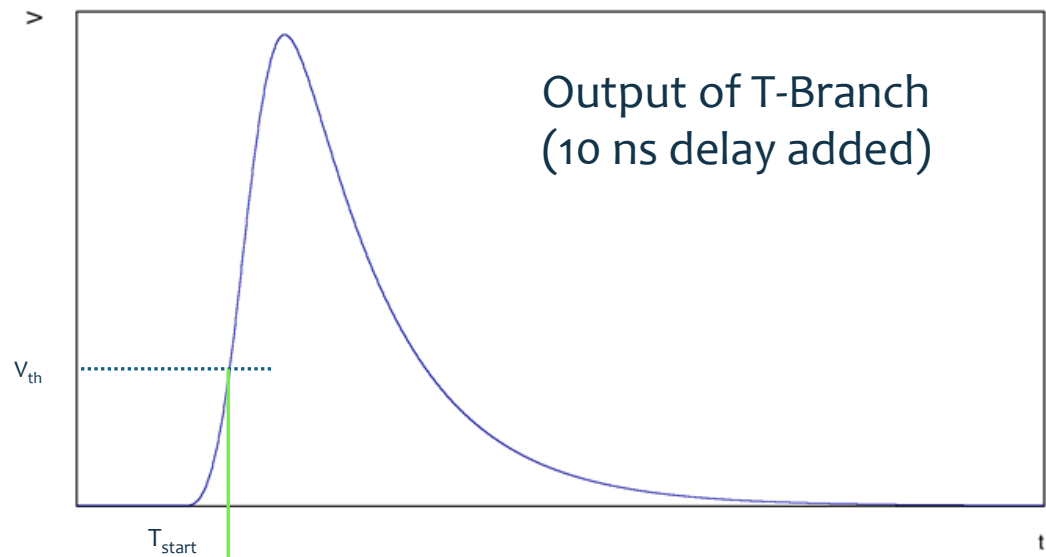
- Status of full digitization
  - ✓ Signal production (ionization, sampling of drift & multiplication, induction) implemented but not tuned
  - ✓ Model to simulate electronics output implemented but not complete (E-branch trigger from T-branch, sampling and hold, ... missing)
- Implement more details in digitization for electronics
  - To make digitization more complete and realistic
  - To be able to fix the electronics part to tune the signal producing part (inputs of electronics)

# E-branch trigger

A typical input current



- Maximum voltage exceeds threshold
- Sampling start given by T-branch discriminator
- Sampling time is integer multiples of 25ns (default 175 ns same as in cosmic-ray data taking, 150 ns used in this talk)
- $V_{\text{sampled}}$  is close to  $V_{\text{max}}$

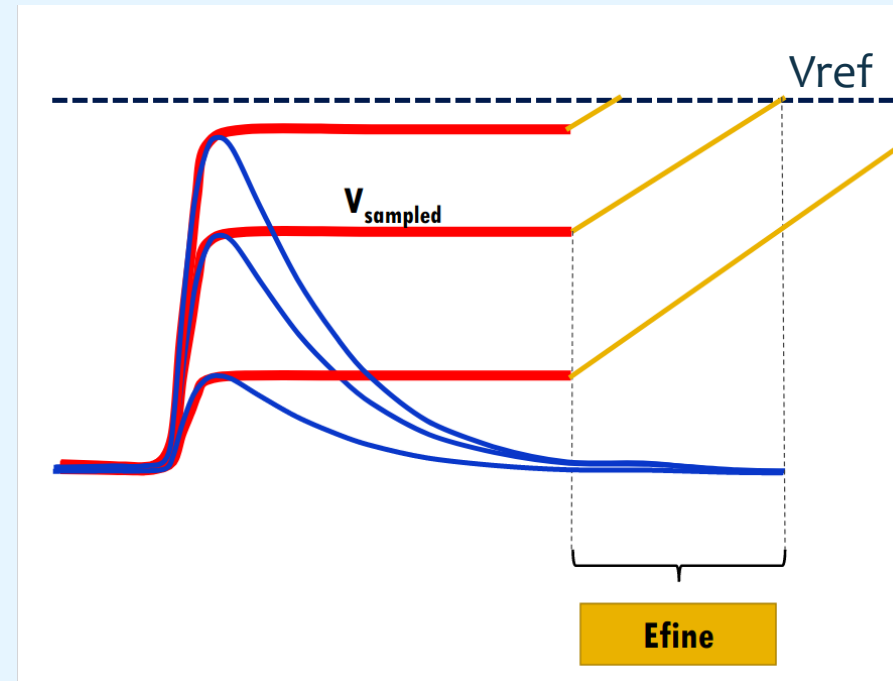


# Charge calibration in practice: $E_{\text{fine}}-Q_{\text{in}}$ curves

$E_{\text{fine}} \rightarrow Q$

$V_{\text{sampled}} \xrightarrow[\text{constant current}]{\text{charge with a}} V_{\text{ref}}$

$E_{\text{fine}}$  vs  $V_{\text{sampled}}$  relation is linear

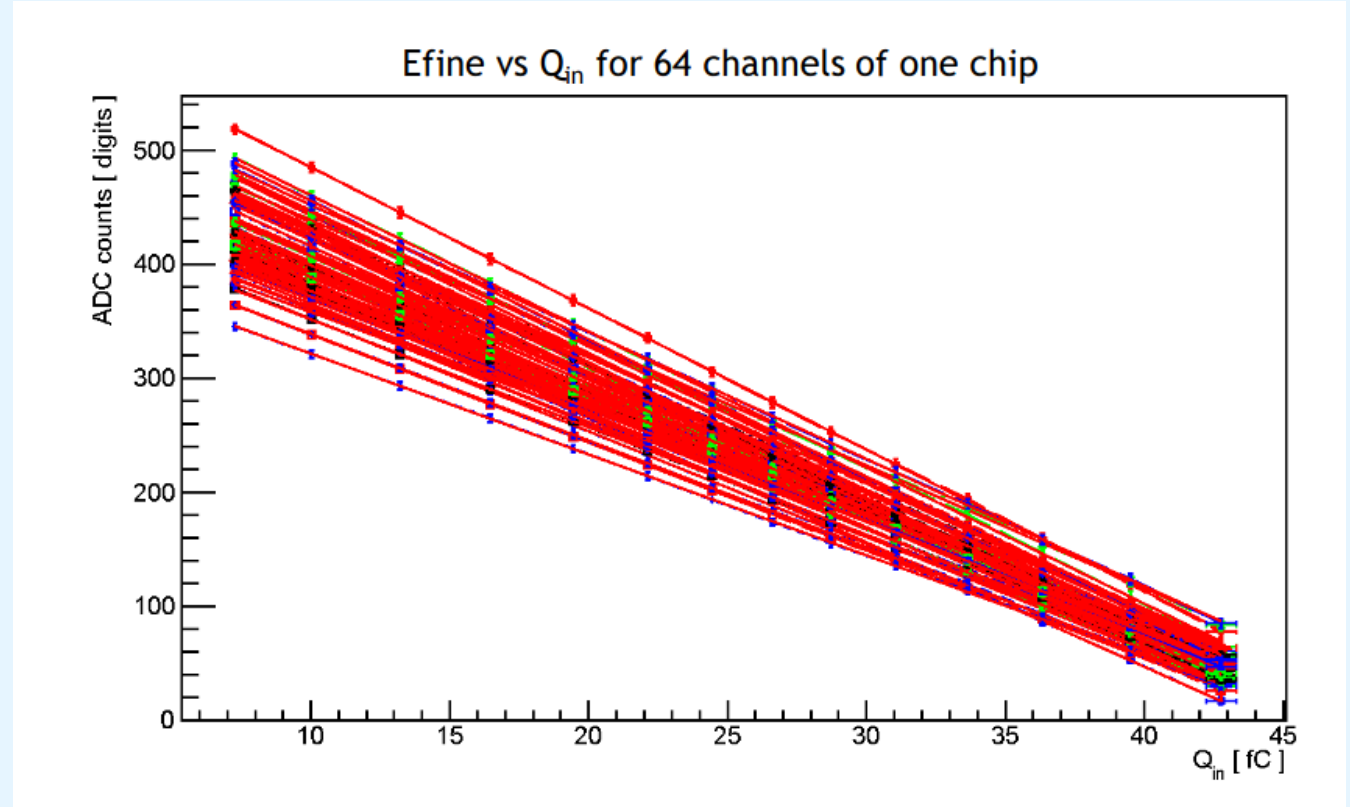


- $E_{\text{fine}}$  depends on sampling voltage
- $E_{\text{fine}}$  and  $Q_{\text{in}}$  are linear

# Charge calibration in practice: $E_{\text{fine}}-Q_{\text{in}}$ curves

Input signal: 1 ns , rectangle  
threshold=3~4 fC in T-branch,  $T_{\text{sampling}}=150$  ns

Because of inconsistency of electronics ,  
 $E_{\text{fine}}$  vs  $Q_{\text{in}}$  conversion should be  
calibrated channel-by-channel

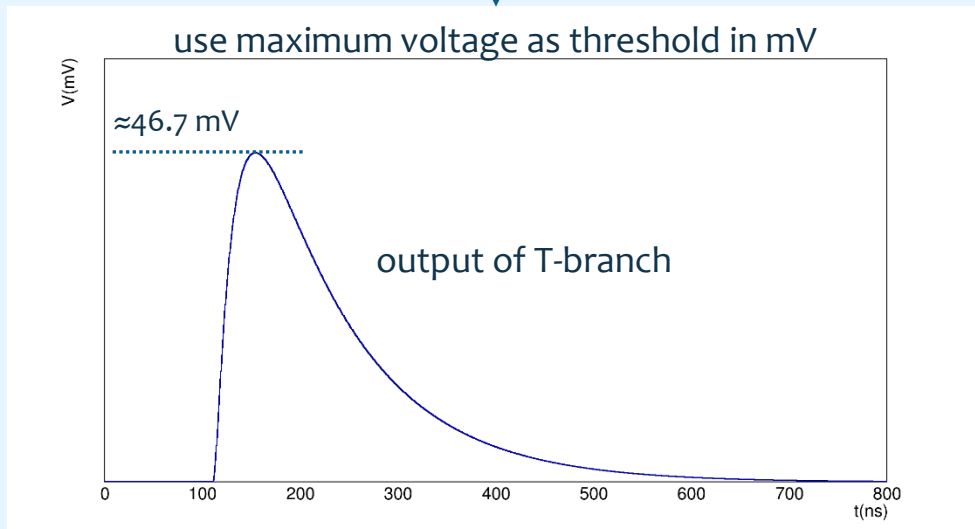
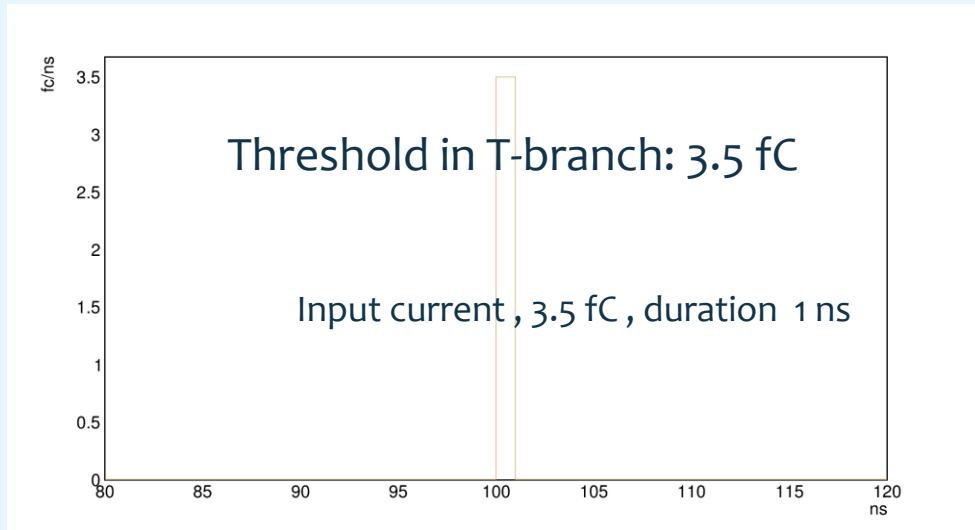
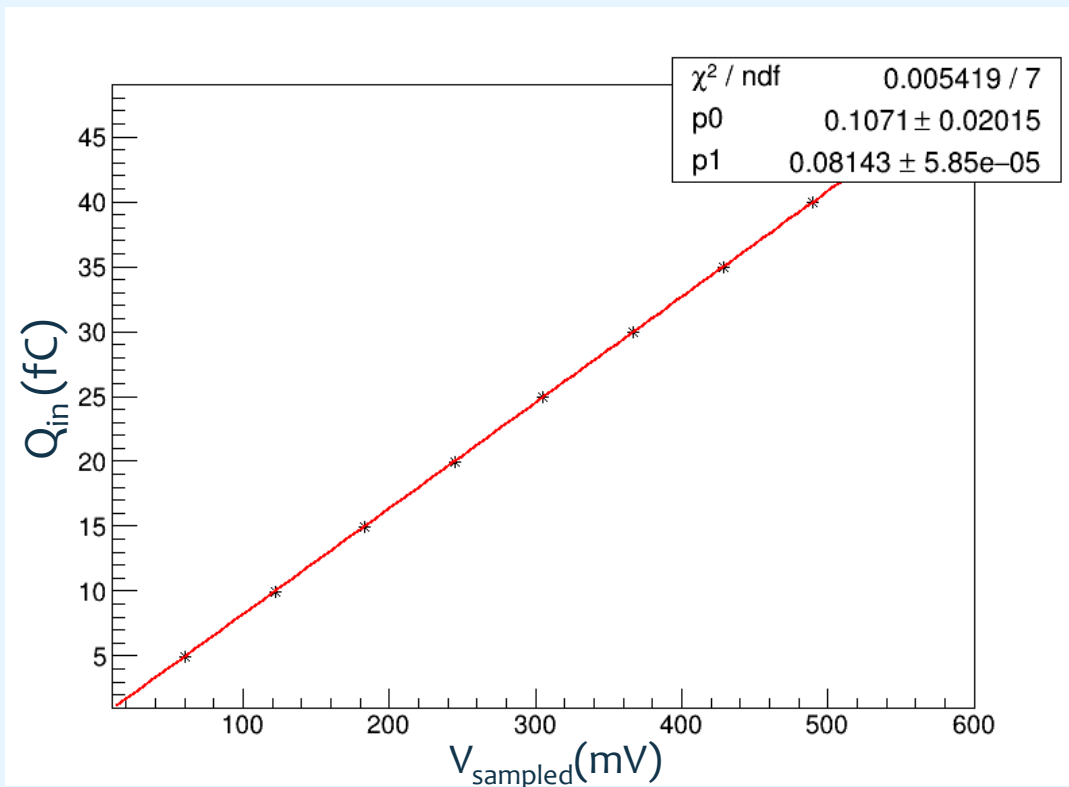


# Charge calibration in simulation: $V_{\text{sampled}}-Q_{\text{in}}$ curve

- Good linearity of  $V_{\text{sampled}}$  vs  $E_{\text{fine}}$   
 $\Rightarrow V_{\text{sampled}}-E_{\text{fine}}$  conversion is not simulated
- ✓ Use  $V_{\text{sampled}}-Q_{\text{in}}$  relationship in simulation

different input charge (current shape: 1 ns , rectangle)

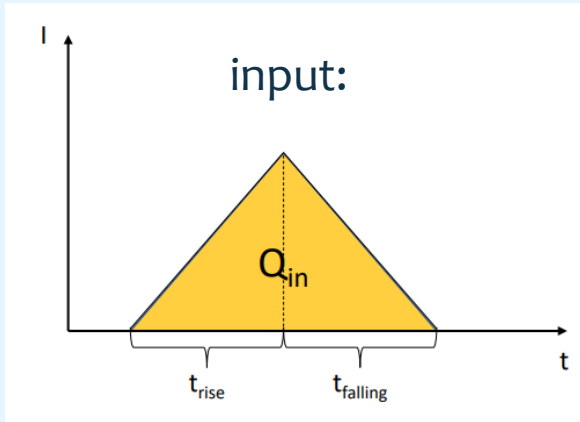
$T_{\text{sampling}}=150$  ns



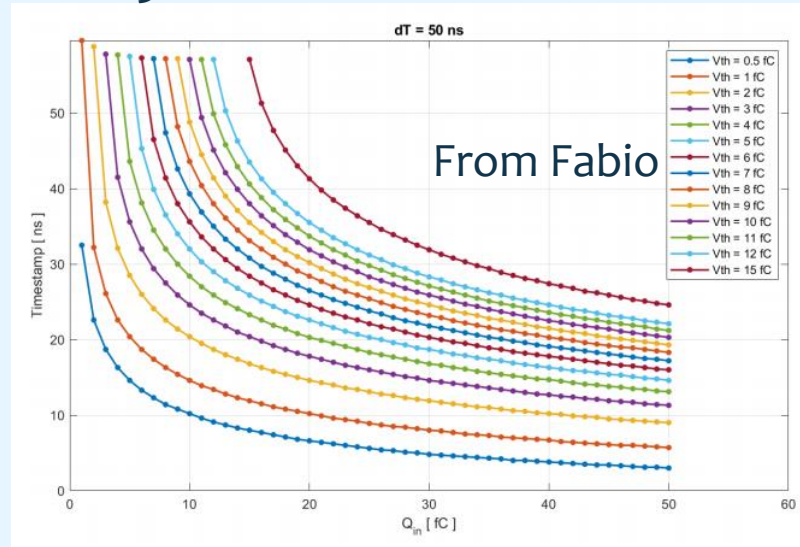
# Update of CgemDigitizerSvc

- Improve digitization of E-Branch (input current -> voltage)
- Use thresholds from LUT file (CGEM\_cosmic\_look\_up\_table\_from\_10\_to\_17.root)
- Get sampling voltage then charge obtained by the  $V_{\text{sampled}}-Q_{\text{in}}$  curve

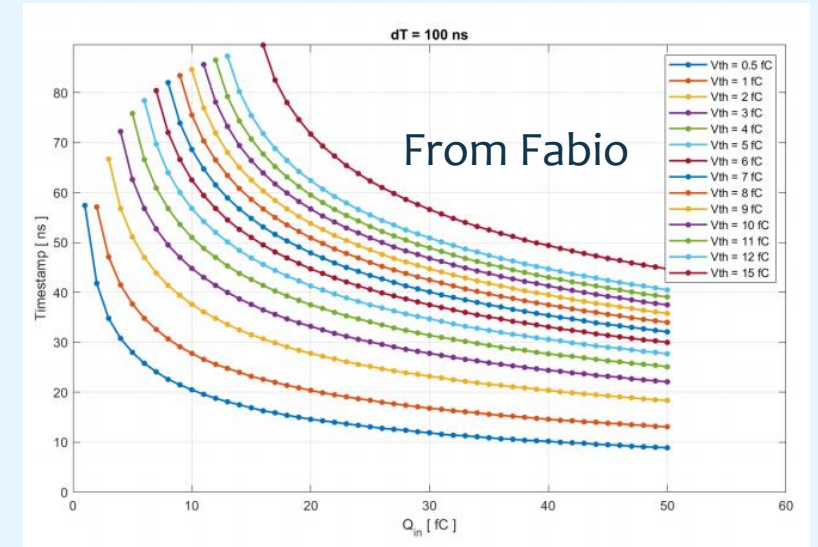
# Check of Digitization: time walk



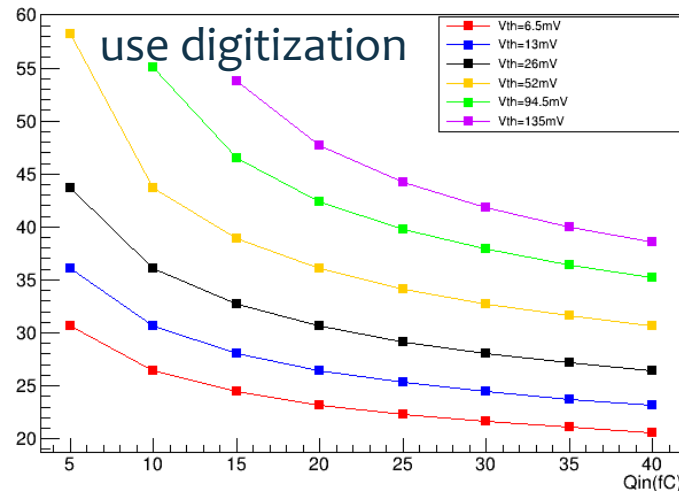
50ns



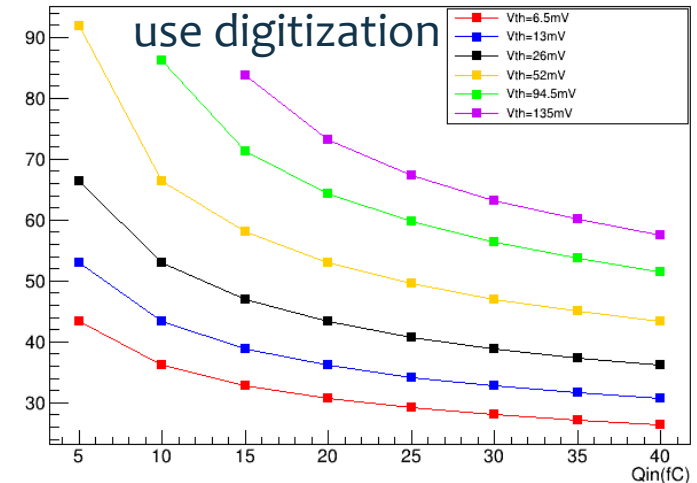
100ns



use digitization



use digitization



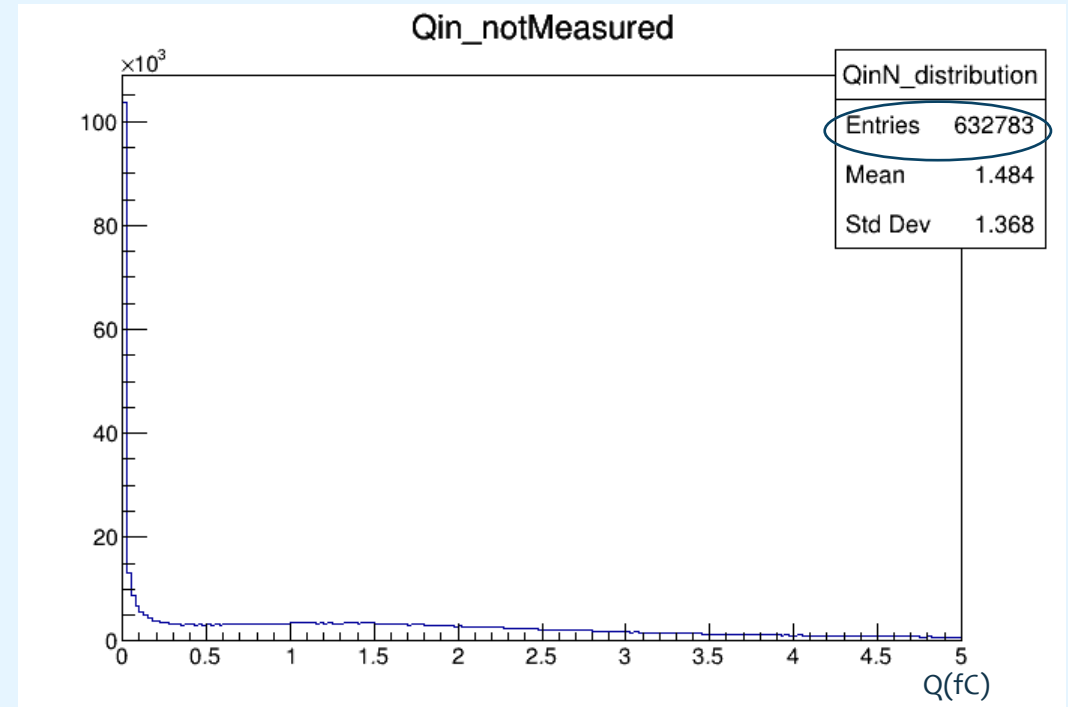
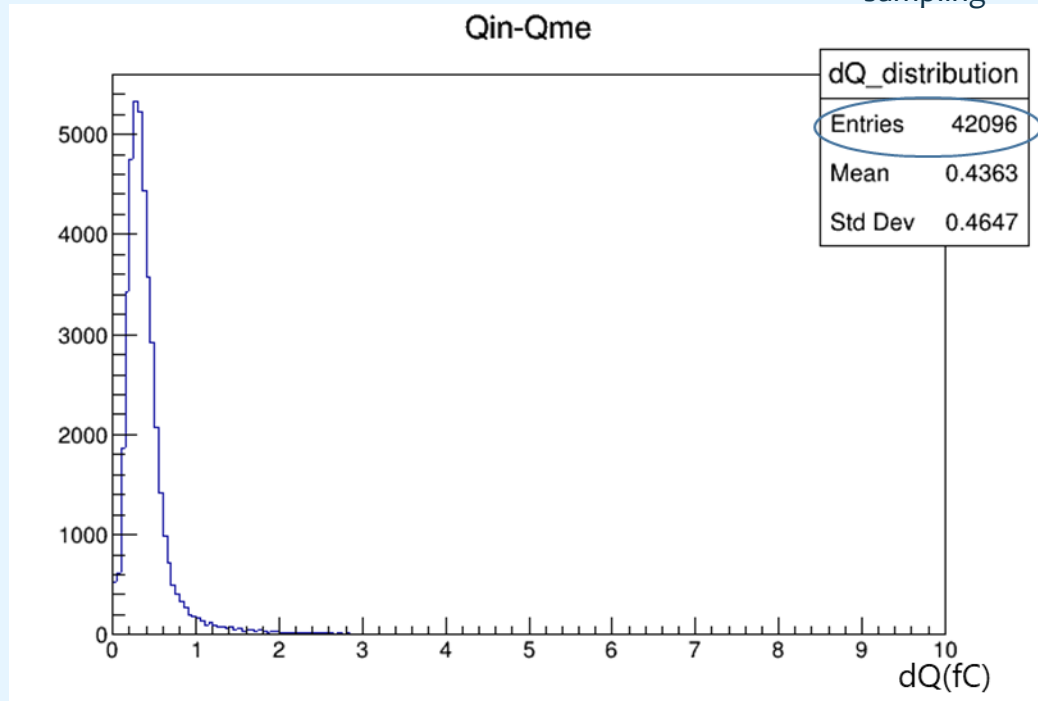
- Same input to get time walk in digitization
- Time walk behavior is similar
- But it seems there is a time shift between the two sets of results

threshold: 13 mV  $\Leftrightarrow$  1 fC



# Check of Digitization: charge measurement

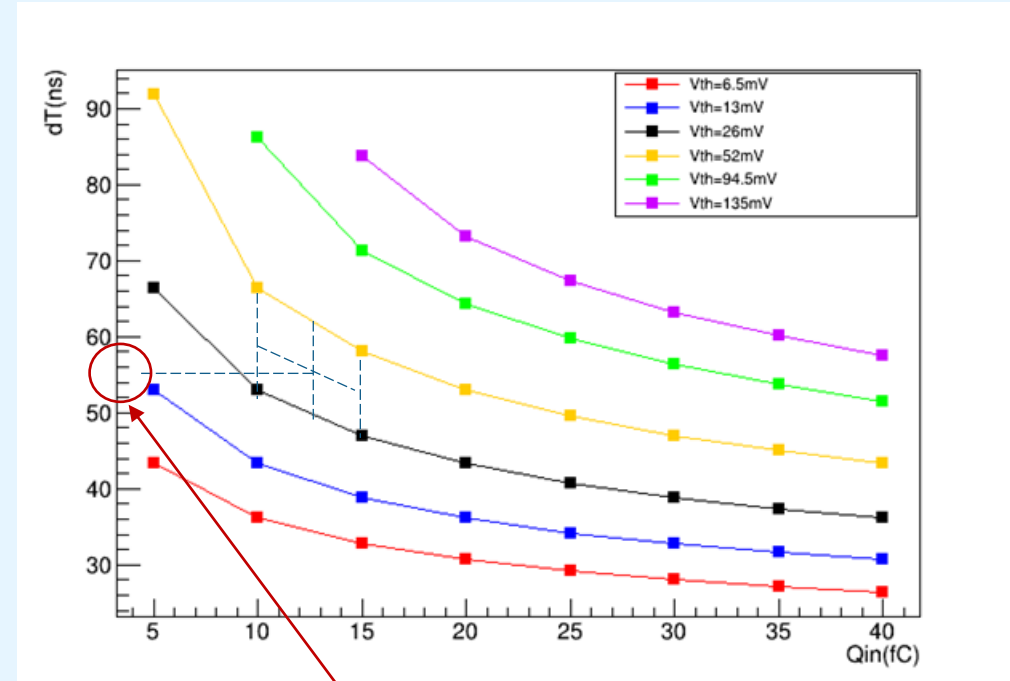
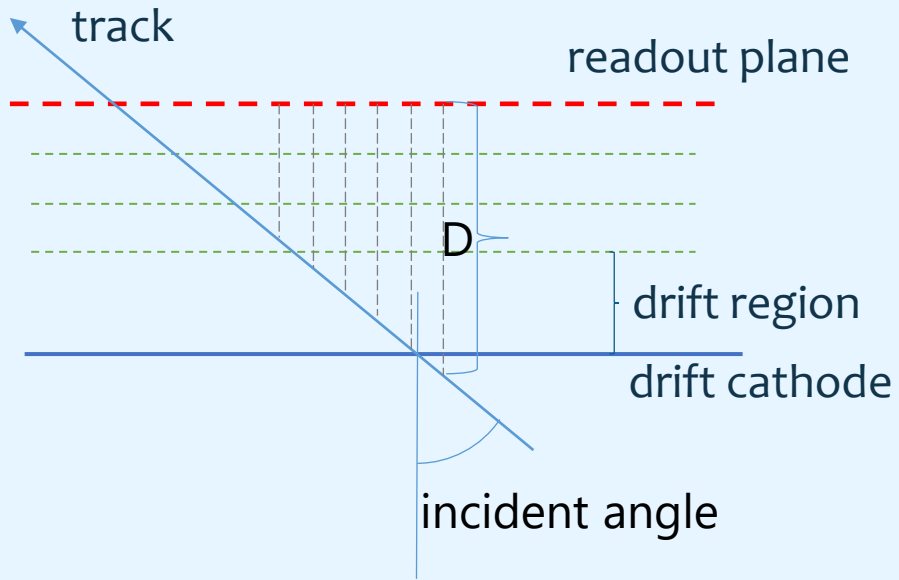
Innermost layer : thresholds from LUT,  $T_{\text{sampling}} = 150 \text{ ns}$



$Q_{\text{in}}$  : input charge (simulation)

$Q_{\text{measured}}$  : measured charge via  $V_{\text{samp}ped}$  &  $V_{\text{samp}ped} - Q_{\text{in}}$  conversion

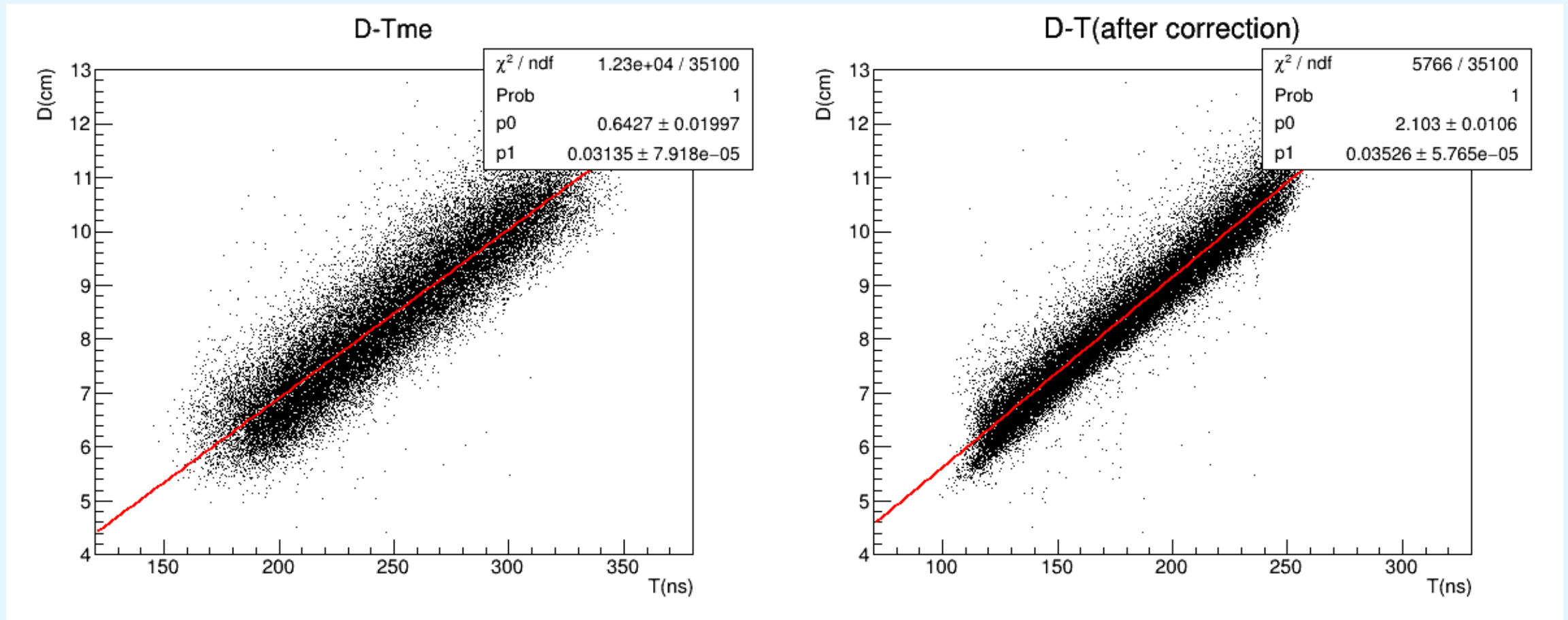
# Check of Digitization: drift distance vs time



Time correction : linear interpolation of threshold and  $Q$

# Check of Digitization: drift distance vs time

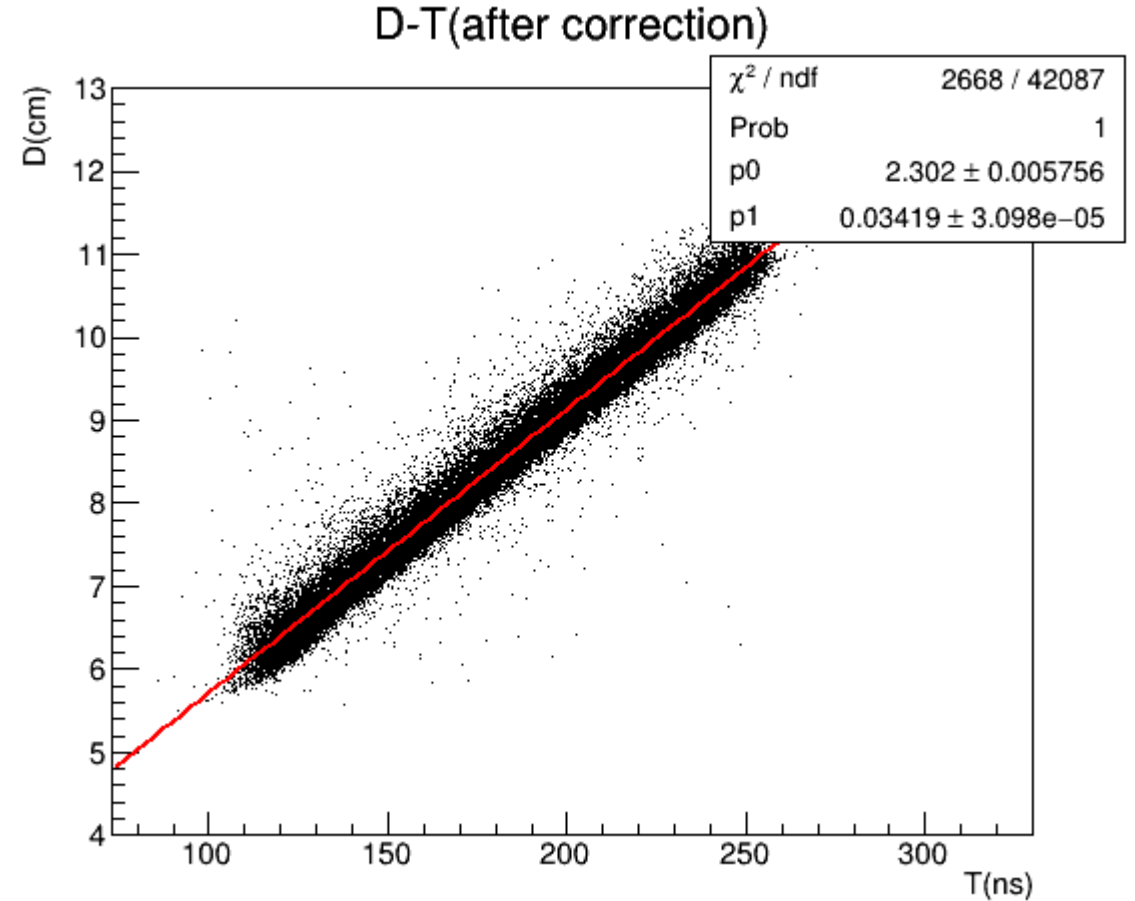
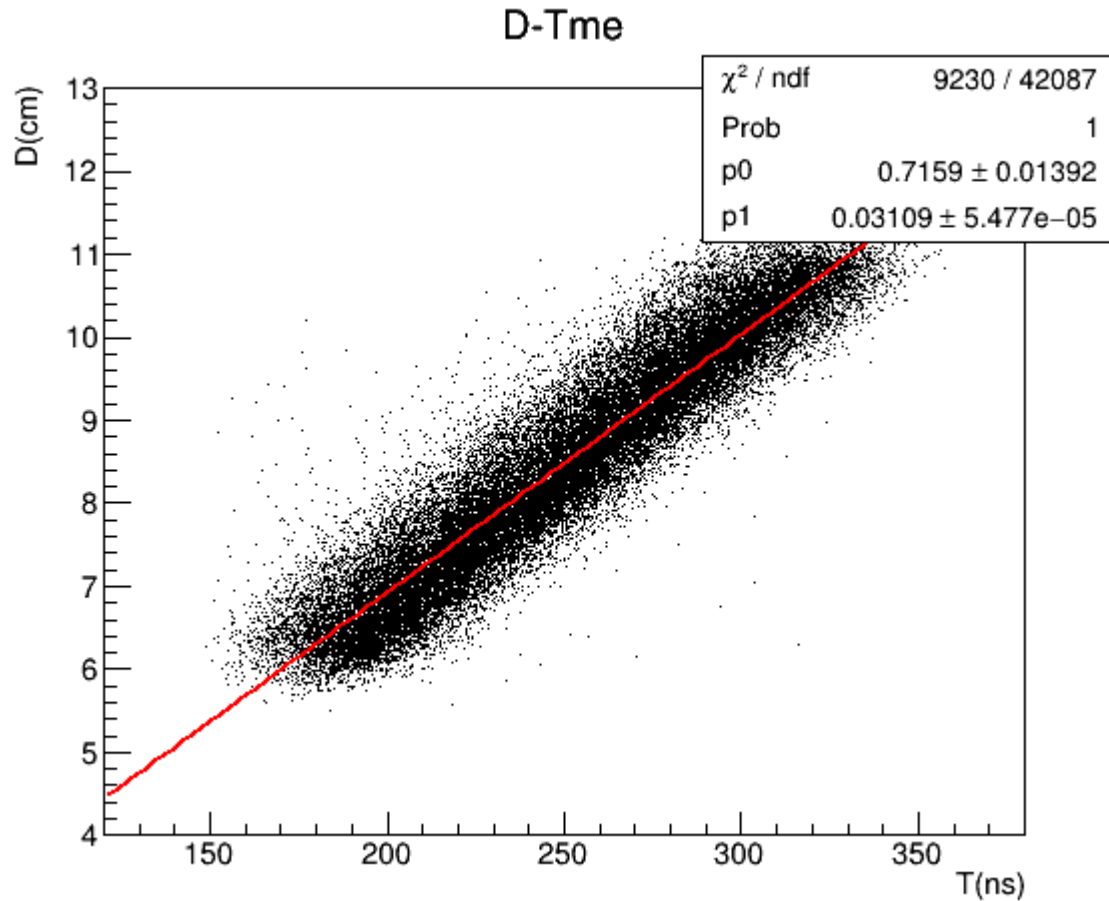
Innermost layer : thresholds from LUT ,  $T_{\text{sampling}} = 150 \text{ ns}$  ,  $e^-$  ,  $P_t = 1 \text{ GeV}$



Incident angle = 0.6 rad

# Check of Digitization: drift distance vs time

Innermost layer : thresholds from LUT ,  $T_{\text{sampling}} = 150\text{ns}$  ,  $e^-$  ,  $P_t = 1\text{ GeV}$



Incident angle = 1.0 rad

# Summary

- Improved digitization package.
  - ✓ E-Branch , convert input current to voltage
  - ✓ charge measurement use  $V_{\text{sampled}} - Q_{\text{in}}$  relation
- check of charge measurement and D-T relation
- Results reasonable
- The new version of digitization is to be uploaded soon.